


PCN Number:	20211029000.2		PCN Date:	November 08, 2021	
Title:	Qualification of TI Chengdu as an additional Assembly and Test site for Select Devices				
Customer Contact:	PCN Manager	Dept:	Quality Services		
Proposed 1st Ship Date:	May 08, 2022	Estimated Sample Availability:	Date provided at sample request		
Change Type:					
<input checked="" type="checkbox"/>	Assembly Site	<input type="checkbox"/>	Design	<input type="checkbox"/>	Wafer Bump Site
<input type="checkbox"/>	Assembly Process	<input type="checkbox"/>	Data Sheet	<input type="checkbox"/>	Wafer Bump Material
<input checked="" type="checkbox"/>	Assembly Materials	<input type="checkbox"/>	Part number change	<input type="checkbox"/>	Wafer Bump Process
<input type="checkbox"/>	Mechanical Specification	<input checked="" type="checkbox"/>	Test Site	<input type="checkbox"/>	Wafer Fab Site
<input checked="" type="checkbox"/>	Packing/Shipping/Labeling	<input type="checkbox"/>	Test Process	<input type="checkbox"/>	Wafer Fab Materials
		<input type="checkbox"/>		<input type="checkbox"/>	Wafer Fab Process
PCN Details					
Description of Change:					

Assembly Site		
UTAC	Assembly Site Origin (22L)	ASO: NSE
CDAT	Assembly Site Origin (22L)	ASO: CDA

Sample product shipping label (not actual product label)


G3 = Matte Sn
G4 = NiPdAu



MADE IN: Malaysia
2DC: 20:

MSL 2 / 260C / 1 YEAR	SEAL DT
MSL 1 / 235C / UNLIM	03/29/04

OPT:
ITEM: 39
LBL: 5A (L)T0:1750



G4

(1P) SN74LS07NSR
(Q) 2000 (D) 0336
(31T) LOT: 3959047MLA
(4W) TKY (1T) 7523483SI2
(P)
(2P) REV: (V) 0033317
(20L) CSO: SHE (21L) CCO: USA
(22L) ASO: MLA (23L) ACO: MYS

Product Affected:

LMR33620AQ5RNXRQ1	LMR33620BQRNXTQ1	LMR33620CQRNXRQ1	LMR33630BQRNXTQ1
LMR33620AQ5RNXTQ1	LMR33620CQ3RNXRQ1	LMR33620CQRNXTQ1	LMR33630CQRNXRQ1
LMR33620AQRNXRQ1	LMR33620CQ3RNXTQ1	LMR33630AQRNXRQ1	LMR33630CQRNXTQ1
LMR33620AQRNXTQ1	LMR33620CQ5RNXRQ1	LMR33630AQRNXTQ1	
LMR33620BQRNXRQ1	LMR33620CQ5RNXTQ1	LMR33630BQRNXRQ1	

Qualification Report

Automotive New Product Qualification Summary (As per AEC-Q100 and JEDEC Guidelines)

Approved 28-Sept-2020

Qualification Results

Data Displayed as: Number of lots / Total sample size / Total failed

Type	#	Test Spec	Min Lot Qty	SS/Lot	Test Name / Condition	Duration	Qual Device: LMR33630CQRNXRQ1 CDAT	Qual Device: LMR33630CQRNXRQ1 UTL1	QBS Package Qual UTL1: LMR33620CQRNXTQ1
Test Group A – Accelerated Environment Stress Tests									
PC	A1	JEDEC J-STD-020 JESD22-A113	3	231	Automotive Preconditioning	Level 2-260C	Pass	-	Pass
bHAST	A2	JEDEC JESD22-	3	77	Biased HAST, 110C/85%RH	264 Hours	3/231/0	-	-

			A101							
uHAST	A3	JEDEC JESD22- A102	3	77	Unbiased HAST, 110C/85%RH	264 Hours	3/231/0	-	-	
THB		JEDEC JESD22- A101	3	77	Biased Temperature and Humidity, 85C/85%RH	1000 Hours	-	-	3/231/0	
AC		JEDEC JESD22- A102	3	77	Autoclave 121C	96 Hours	-	-	3/231/0	
TC	A4	JEDEC JESD22- A104 and Appendix 3	3	77	Temperature Cycle, -65/150C	500 Cycles	3/231/0	-	3/231/0	
PTC	A5	JEDEC JESD22- A105	1	45	Power Temperature Cycle	1000 Cycles	1/44/1 (Note 1)	-	1/45/0	
HTSL	A6	JEDEC JESD22- A103	1	45	High Temp. Storage Life, 150C	1000 Hours	3/231/0	-	3/231/0	
Test Group B – Accelerated Lifetime Simulation Tests										
HTOL	B1	JEDEC JESD22- A108	3	77	Life Test, 125C	1000 Hours	3/231/0	-	3/231/0	
ELFR	B2	AEC Q100- 008	3	800	Early Life Failure Rate, 125C	48 Hours	3/2400/0	-	3/2400/0	
EDR	B3	AEC Q100- 005	3	77	NVM Endurance, Data Retention, and Operational Life	10000 Cycles	3/231/0	-	-	
Test Group C – Package Assembly Integrity Tests										
WBS	C1	AEC Q100- 001	1	30	Bond Shear (Cpk>1.67)	Wires	N/A	-	N/A	
WBP	C2	MIL- STD883 Method 2011	1	30	Bond Pull (Cpk>1.67)	Wires	N/A	-	N/A	
SD	C3	JEDEC JESD22- B102	1	15	Surface Mount Solderability >95% Lead Coverage	15	1/15/0	-	Pass	
PD	C4	JEDEC JESD22- B100 and B108	3	10	Physical Dimensions (Cpk>1.67)	30 units	3/90/0	-	Pass	
SBS	C5	AEC Q100- 010	3	50	Solder Ball Shear (Cpk>1.67)	Solder Balls	N/A	-	N/A	
LI	C6	JEDEC JESD22- B105	1	50	Lead Integrity	Leads	N/A	-	N/A	
Test Group D – Die Fabrication Reliability Tests										
EM	D1	JESD61	-	-	Electromigratio n	--	Completed Per Process Technology Requirements	Completed Per Process Technology Requirements	Completed Per Process Technology Requirements	
TDDB	D2	JESD35	-	-	Time Dependent Dielectric Breakdown	--	Completed Per Process Technology Requirements	Completed Per Process Technology Requirements	Completed Per Process Technology Requirements	
HCI	D3	JESD60 & 28	-	-	Hot Injection Carrier	--	Completed Per Process Technology Requirements	Completed Per Process Technology Requirements	Completed Per Process Technology Requirements	
NBTI	D4	-	-	-	Negative Bias Temperature	--	Completed Per Process Technology	Completed Per Process Technology	Completed Per Process Technology	

						Instability		Requirements	Requirements	Requirements
SM	D5	-	-	-		Stress Migration	--	Completed Per Process Technology Requirements	Completed Per Process Technology Requirements	Completed Per Process Technology Requirements
Test Group E – Electrical Verification Tests										
HBM	E2	AEC Q100-002	1	3	ESD - HBM	2500 V		1/3/0	1/3/0	1/3/0
CDM	E3	AEC Q100-011	1	3	ESD - CDM	750 V		1/3/0	1/3/0	1/3/0
LU	E4	AEC Q100-004	1	6	Latch-up	+100mA, 150C		1/6/0	1/6/0	1/6/0
ED	E5	AEC Q100-005	3	30	Electrical Distribution	Cpk > 1.67		3/30/0	-	3/90/0

- QBS: Qual By Similarity

- Qual Device LMR33630CQRNXRQ1 is qualified at LEVEL2-260C

A1 (PC): Preconditioning:

Performed for THB, Biased HAST, AC, uHAST, TC & PTC samples, as applicable.

Ambient Operating Temperature by Automotive Grade Level:

Grade 0 (or E): -40°C to +150°C

Grade 1 (or Q): -40°C to +125°C

Grade 2 (or T): -40°C to +105°C

Grade 3 (or I) : -40°C to +85°C

E1 (TEST): Electrical test temperatures of Qual samples (High temperature according to Grade level):

Room/Hot/Cold : HTOL, ED

Room/Hot : THB / HAST, TC / PTC, HTSL, ELFR, ESD & LU

Room : AC/uHAST

Green/Pb-free Status:

Qualified Pb-Free(SMT) and Green

Note 1: 1 fail was attributed to test issue and was discounted. FA available upon request.

For questions regarding this notice, e-mails can be sent to the contacts shown below or your local Field Sales Representative.

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